

$Z \rightarrow \tau\tau$ cross-section measurement at 13TeV

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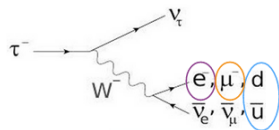
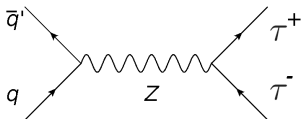
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Introduction

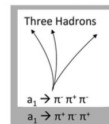
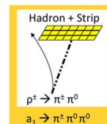
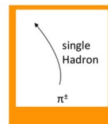
- Goal of the analysis: Measure the $Z \rightarrow \tau\tau$ cross-section at 13 TeV (Important background for $H \rightarrow \tau\tau$ analysis)
- Signal: Drell Yan decaying into two taus, one tau decays into an electron or muon and neutrinos, the second one decays into hadrons and neutrino



Tau Reconstruction

- HPS (Hadron+Strips Algorithm to reconstruct hadronic decay of taus)
- It is reconstructed in 3 different modes

	Decay Mode	Resonance	$B[\%]$
leptonic decays	$\tau^- \rightarrow e^- \bar{\nu}_e \nu_\tau$		17.8
	$\tau^- \rightarrow \mu^- \bar{\nu}_\mu \nu_\tau$		17.4
1 - prong decays	$\tau^- \rightarrow \pi^- \nu_\tau$	$\pi(140)$	11.6
	$\tau^- \rightarrow \pi^- \pi^0 \nu_\tau$	$\rho(770)$	26.0
	$\tau^- \rightarrow \pi^- \pi^0 \pi^0 \nu_\tau$	$a_1(1260)$	10.8
	$\tau^- \rightarrow \pi^- \pi^+ \pi^- \nu_\tau$	$a_1(1260)$	9.8
3 - prongs decays	$\tau^- \rightarrow \pi^- \pi^+ \pi^- \pi^0 \nu_\tau$		4.8
	Other hadronic modes		1.7
	All hadronic modes		64.8



Analysis anatomy

- Final state with muon, hadronic tau and missing transverse momentum
- The full background model consists of:
 - reducible with leptons from b/c quarks and/or W decays:
 - ttbar
 - diboson production WW, WZ, ZZ (small)
 - single top tW (very small, neglected)
 - reducible with fake leptons:
 - W+jets, QCD
- All backgrounds are measured in control regions where their contributions are enhanced and extrapolated using samples of same-sign (SS) and opposite-sign (OS) events from data, for which the electron or muon isolation requirement is inverted
- Veto events with more than 1 good identified and isolated muon or electron in the event
- Veto events with 2 good electrons and muons since $Z \rightarrow \mu\mu$ in particular can contaminate the signal phase space
- Require events with 0 b-tagged jets

Event selection

- $\mu \tau$ channel

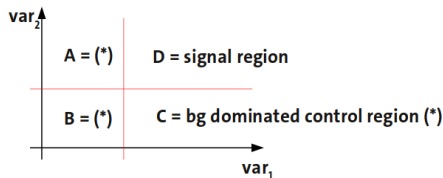
- Find a good muon in event (apply p_T , η , muon Identification, Muon Isolation and impact parameter cut)
- Find a good tau in the event (apply p_T , η , decay Mode Finding, Isolation, Anti-Muon discriminator and Anti-Electron discriminator)
- Check distance ΔR between muon and tau to greater than 0.5.
- Make sure the $Z \rightarrow \mu\mu$ process is not contaminating the mu-tau yield.

- $e \tau$ channel

- Find a good electron in event (apply p_T , η , muon Identification, Muon Isolation and impact parameter cut)
- Find a good tau in the event (apply p_T , η , decay Mode Finding, Isolation, Anti-Muon discriminator and Anti-Electron discriminator)
- Check distance ΔR between electron and tau to greater than 0.5.
- Make sure the $Z \rightarrow ee$ process is not contaminating the e-tau yield.
Reject events with extra electron and jets.

QCD Background Estimation. ABCD Method

- If search region is defined by sequential cuts, e.g. on var_1 and var_2 (with discriminative power, e.g. isolation and charge)

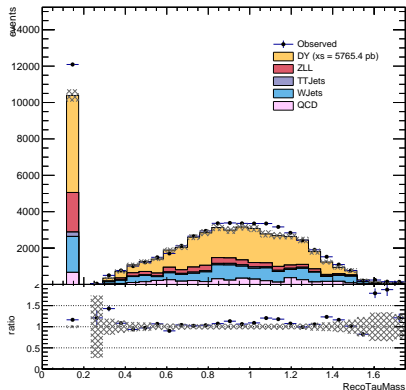


- If variables are uncorrelated (has to be verified): $N_D = \frac{N_C N_A}{N_B}$
 - shape of var_1 distribution independent of choice of var_2
 - background in signal region predicted by scaling of control sample
 - Modification for correlated variables possible, however challenging
 - For the analysis OS/SS=1.06

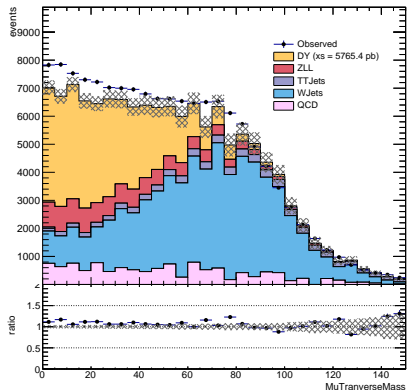
Control Plots mutau channel

$$m_T(l, E_T^{\text{miss}}) = \sqrt{(E_l + E_T^{\text{miss}})^2 + (\vec{p}_l + \vec{E}_T^{\text{miss}})^2}$$

OS Tight Tau Iso

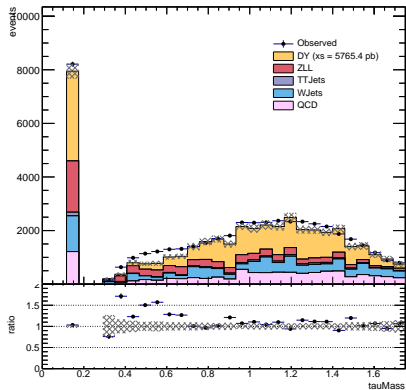


OS Tight Tau Iso

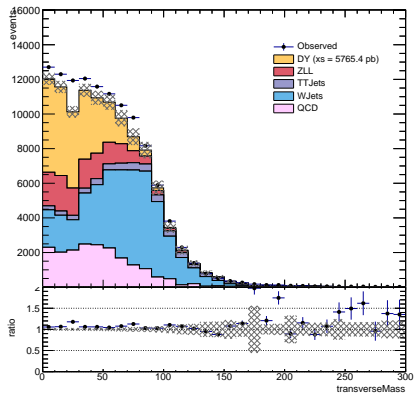


Control Plots etau channel

OS Tight Tau Iso

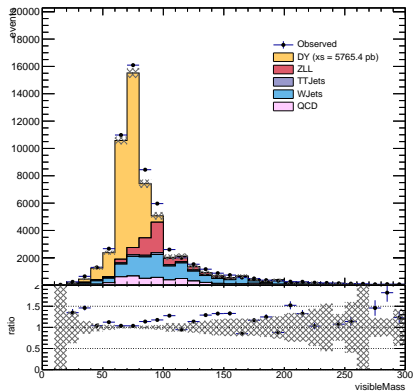


OS Tight Tau Iso

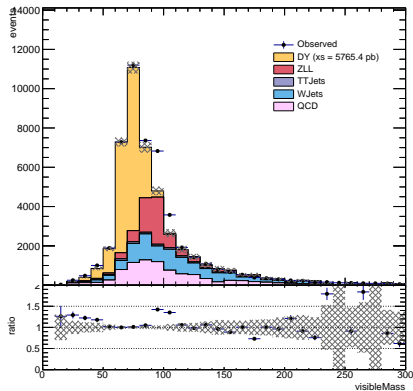


Final plots. Mutau channel and etau channel

OS Tight Tau Iso

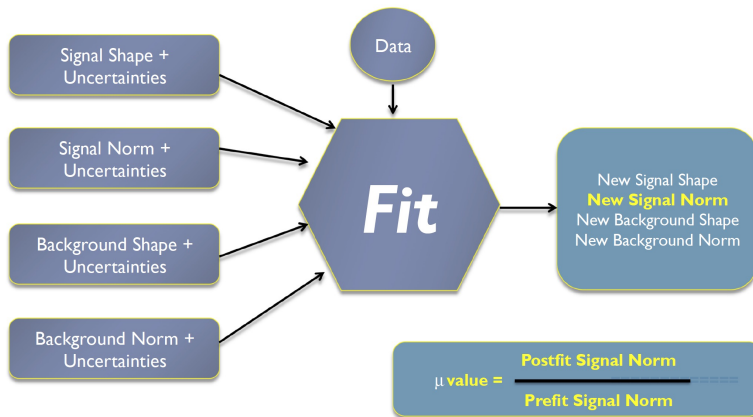


OS Tight Tau Iso



Systematic uncertainties

- Muon ID efficiency: 2%
- Muon trigger eff.: 2%
- Electron trigger eff.: 2%
- Electron ID eff.: 2%
- Tau ID eff.: 5%
- W+Jets cross-section: 10%
- Ttbar cross-section: 10%
- QCD background estimation: 30%
- Integrated luminosity: 2.5%



Combine tool

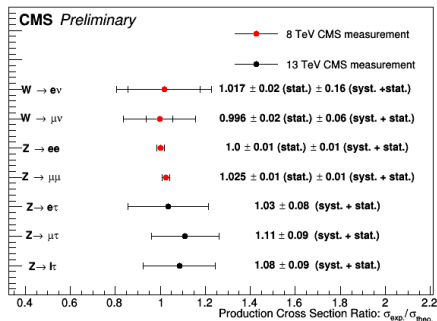
- Fit is performed using Higgs Combined Tool
- Combine provides a command line interface to many different statistical techniques available inside RooFit/RooStats used widely inside CMS
- The input to combine, which defines the details of the experiment, is a datacard file
- This plain ASCII file contains:
 - the number of independent sources of systematic uncertainties
 - the number of observables
 - the number of independent sources of systematic uncertainties
 - the number of events expected, for each bin and process
 - the systematic uncertainties with columns reporting the relative effect on the rate of each process in each channel

Cross Section Measurement

- Theoretical cross section is: 5765 pb
- The cross section is obtained for each final state with the following formula:

$$\sigma(pp \rightarrow ZX) \cdot \mathcal{B}(Z \rightarrow \tau^+ \tau^-) = \frac{N}{\mathcal{A} \epsilon \mathcal{B}' \mathcal{L}}$$

where N is the number of extracted signal events, \mathcal{A} is the acceptance of signal events, ϵ is the signal selection efficiency, \mathcal{B}' is the branching fraction of the decay mode considered, and \mathcal{L} is the integrated luminosity ($35.9 fb^{-1}$)



- A measurement of the cross section for the process $pp \rightarrow ZX$ with $Z \rightarrow \tau^+\tau^-$) has been performed based on the $\tau_e\tau$ and $\tau_\mu\tau$ final state
- A clear signal is established in the visible mass distributions for both channels.
- QCD multijet process was obtained from data and the rest of the background through dedicated MC simulations.
- The cross section calculated using a maximum likelihood fit is consistent with theoretical expectations with a ratio of 1.08 ± 0.09 .